

## Notice of References Cited

Application/Control No. 09/776,981	Applicant(s)/Patent Under Reexamination LEE ET AL.		
Examiner	Art Unit		
Fric Chang	2116	Page 1 of 1	

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	А	US-6,553,525 B1	04-2003	Shephard, III, Philip George	714/733
	В	US- ·			
	С	US-			
	D	US-			
	Ę	US-			
	F	US-	•		
	G	US-			
	Н	US-			
	ı	US-			
	J	US-			
	К	US-			
	٦	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*	\$	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 06103249 A	04-1994	Japan	NAKANISHI et al.	G06F 15/16
	0					
	Р					
	Q					
	R					
	s					
	Т					,

## **NON-PATENT DOCUMENTS**

NOT ALL TO SOUTH TO				
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)		
	U			
	V			
	w			
	x			

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.